

TECHNICAL SPECIFICATION

**Nanomanufacturing - Key control characteristics -
Part 6-35: Graphene-related products - Density: free-pouring, tapping and
compressing method**

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

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IEC TS 62607-6-35 has been prepared by IEC technical committee 113: Nanotechnology for electrotechnical products and systems. It is a Technical Specification.

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Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this Technical Specification is English.